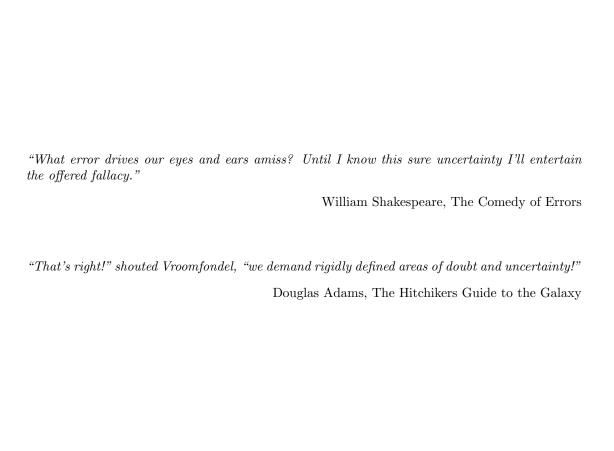
Declaration of Authorship

Laurence Stant (Author)

I confirm that the submitted work is my own work and that I have clearly identified and fully acknowledged all material that is entitled to be attributed to others (whether published or unpublished) using the referencing system set out in the programme handbook. I agree that the University may submit my work to means of checking this, such as the plagiarism detection service Turnitin UK. I confirm that I understand that assessed work that has been shown to have been plagiarised will be penalised.

The authors confirm that data underlying the findings are available without restriction. Details of the data and how to request access are available from the University of Surrey publications repository at http://epubs.surrey.ac.uk/blahTBD

Date



Abstract

Abstract goes here

Research Outcomes

Publications

- H. Votsi, L. T. Stant, M. J. Salter, C. Li, N. M. Ridler, and P. H. Aaen, "An interferometric characterization technique for extreme impedance microwave devices," in 2020 94th ARFTG Microwave Measurement Conference (ARFTG), submitted.
- [2] M. J. Salter, L. T. Stant, K. Buisman, and T. Nielsen, "An inter-laboratory comparison of NVNA measurements," in 2011 Workshop on Integrated Nonlinear Microwave and Millimetre-Wave Circuits, Brive, Jul. 2018.
- [3] L. T. Stant, M. J. Salter, N. M. Ridler, D. F. Williams, and P. H. Aaen, "Propagating measurement uncertainty to microwave amplifier nonlinear behavioural models," *IEEE Trans. Microw. Theory Techn.*, Nov. 2018.
- [4] L. T. Stant, P. H. Aaen, and N. M. Ridler, "Evaluating residual errors in waveguide VNAs from microwave to submillimetre-wave frequencies," *IET Microwaves Antennas Propag.*, vol. 11, no. 3, pp. 324–329, Feb. 2017. DOI: 10.1049/iet-map.2016.0455.
- [5] —, "Comparing methods for evaluating measurement uncertainty given in the JCGM 'evaluation of measurement data' documents," *Measurement*, vol. 94, pp. 847–851, Dec. 2016. Doi: 10.1016/j.measurement.2016.08.015.

Presentations

- [1] L. T. Stant, "Comparing methods for evaluating measurement uncertainty given in the JCGM 'evaluation of measurement data' documents," 2nd NPL Postgraduate Institute Annual Conference, Teddington, UK, Oct. 2017.
- [2] —, "Comparing methods for evaluating measurement uncertainty given in the JCGM 'evaluation of measurement data' documents," Faculty of Engineering and Physical Sciences Annual Festival of Research, University of Surrey, Jun. 2017.
- [3] —, "Evaluating measurement uncertainty in microwave and terahertz frequency metrology," 6th Annual Postgraduate Research Conference, University of Surrey, Apr. 2016.
- [4] L. T. Stant, P. H. Aaen, and N. M. Ridler, "Evaluating residual errors in waveguide network analysers from microwave to submillimetre-wave frequencies," in *IET Colloquium on Millimetre-Wave and Terahertz Engineering & Technology 2016*, Institution of Engineering and Technology (IET), 2016. DOI: 10.1049/ic.2016.0016.

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